Welcome to Galaxy Examinator reports

Date: Tue Sep 3 00:34:16 2024
Product :
LotID :

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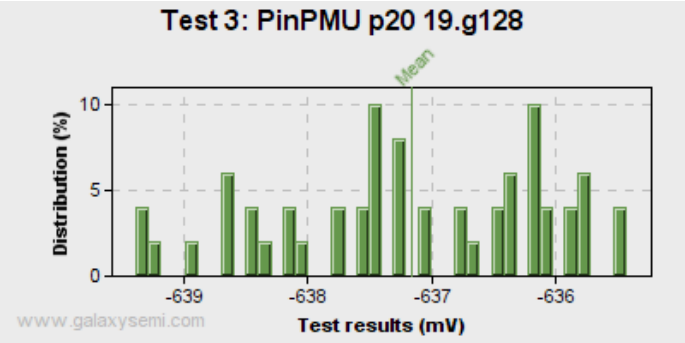
Tests Statistics

Test	Name	Type	Low L.	High L.	Source	Execs	Fails	Mean	Sigma	Cp	Cpk	Yield
0	Functional_T1	F	n/a .	n/a .	Samples	50	0	n/a .	n/a .	n/a .	n/a .	100.00 %
1	Functional_T2	F	n/a .	n/a .	Samples	50	0	n/a .	n/a .	n/a .	n/a .	100.00 %
2	Functional_T3	F	n/a .	n/a .	Samples	50	0	n/a .	n/a .	n/a .	n/a .	100.00 %
3	PinPMU p20 19.g128	P	−1200 mV	−100 mV	Samples	50	0	−637.161 mV	1.09672 mV	167.2	163.3	100.00 %
4	PinPMU p21 19.g126	P	−1200 mV	−100 mV	Samples	50	0	−637.269 mV	1.06833 mV	171.6	167.6	100.00 %
5	PinPMU p22 19.e126	P	−1200 mV	−100 mV	Samples	50	0	−637.096 mV	1.06354 mV	172.4	168.3	100.00 %
6	PinPMU p23 19.e124	P	−1200 mV	−100 mV	Samples	50	0	−637.092 mV	1.01629 mV	180.4	176.2	100.00 %
7	PinPMU p40 19.e130	P	−1200 mV	−100 mV	Samples	50	0	−637.646 mV	1.2127 mV	151.2	147.8	100.00 %
8	PinPMU p41 19.e139	P	−1200 mV	−100 mV	Samples	50	0	−637.829 mV	1.2408 mV	147.8	144.5	100.00 %
9	PinPMU p42 19.e147	P	−1200 mV	−100 mV	Samples	50	0	−638.176 mV	1.14196 mV	160.5	157.1	100.00 %
10	PinPMU p43 19.e151	P	−1200 mV	−100 mV	Samples	50	0	−637.78 mV	1.19472 mV	153.5	150.0	100.00 %
11	PinPMU p50 19.e128	P	−1200 mV	−100 mV	Samples	50	0	−637.068 mV	1.2283 mV	149.3	145.7	100.00 %
12	PinPMU p51 19.g149	P	−1200 mV	−100 mV	Samples	50	0	−633.867 mV	0.569337 mV	322.0	312.6	100.00 %
13	PinPMU p52 19.e137	P	−1200 mV	−100 mV	Samples	50	0	−635.589 mV	1.08386 mV	169.1	164.7	100.00 %
14	PinPMU p53 19.e135	P	−1200 mV	−100 mV	Samples	50	0	−635.818 mV	1.10748 mV	165.5	161.3	100.00 %
15	PinPMU p60 19.g130	P	−1200 mV	−100 mV	Samples	50	0	−635.187 mV	1.09843 mV	166.9	162.4	100.00 %
16	PinPMU p61 19.g104	P	−1200 mV	−100 mV	Samples	50	0	−635.473 mV	1.05163 mV	174.3	169.7	100.00 %
17	PinPMU p62 19.g102	P	−1200 mV	−100 mV	Samples	50	0	−635.515 mV	1.02179 mV	179.4	174.7	100.00 %
18	PinPMU p63 19.e102	P	−1200 mV	−100 mV	Samples	50	0	−635.459 mV	1.0159 mV	180.5	175.7	100.00 %
19	PinPMU p70 19.g139	P	−1200 mV	−100 mV	Samples	50	0	−637.288 mV	1.22761 mV	149.3	145.9	100.00 %
20	PinPMU p71 19.g147	P	−1200 mV	−100 mV	Samples	50	0	−635.878 mV	1.10474 mV	166.0	161.7	100.00 %
21	PinPMU p72 19.e104	P	−1200 mV	−100 mV	Samples	50	0	−635.343 mV	0.747199 mV	245.4	238.8	100.00 %
22	PinPMU p73 19.e108	P	−1200 mV	−100 mV	Samples	50	0	−635.181 mV	0.87077 mV	210.5	204.9	100.00 %
23	PinPMU cs 19.g106	P	−1200 mV	−100 mV	Samples	50	0	−636.27 mV	0.57071 mV	321.2	313.2	100.00 %
24	PinPMU prog 19.g124	P	−1200 mV	−100 mV	Samples	50	0	−637.077 mV	0.950625 mV	192.9	188.3	100.00 %
25	SeqLeakage1 p20 19.g128	P	−30 uA	10 uA	Samples	50	0	−0.715957 uA	0.0262825 uA	253.7	135.9	100.00 %
26	SeqLeakage1 p21 19.g126	P	−30 uA	10 uA	Samples	50	0	−0.72361 uA	0.0284521 uA	234.3	125.6	100.00 %
27	SeqLeakage1 p22 19.e126	P	−30 uA	10 uA	Samples	50	0	−0.722307 uA	0.0258041 uA	258.4	138.5	100.00 %
28	SeqLeakage1 p23 19.e124	P	−30 uA	10 uA	Samples	50	0	−0.721546 uA	0.0204089 uA	326.7	175.1	100.00 %
29	SeqLeakage2 cs 19.g106	P	−30 uA	10 uA	Samples	50	0	0.0033208 uA	0.00999079 uA	667.3	333.5	100.00 %
30	SeqLeakage2 prog 19.g124	P	−30 uA	10 uA	Samples	50	0	−0.000305603 uA	0.00986529 uA	675.8	337.9	100.00 %
31	VBT_outpleakage1 p40 19.e130	P	−10 uA	20 uA	Samples	50	0	0.00150171 uA	0.00942499 uA	530.5	353.7	100.00 %
Test	Name	Type	Low L.	High L.	Source	Execs	Fails	Mean	Sigma	Cp	Cpk	Yield
32	VBT_outpleakage1 p41 19.e139	P	−10 uA	20 uA	Samples	50	0	0.00289367 uA	0.00922327 uA	542.1	361.5	100.00 %
33	VBT_outpleakage1 p42 19.e147	P	−10 uA	20 uA	Samples	50	0	0.000700129 uA	0.0082731 uA	604.4	402.9	100.00 %
34	VBT_outpleakage1 p43 19.e151	P	−10 uA	20 uA	Samples	50	0	0.00194181 uA	0.00967502 uA	516.8	344.6	100.00 %
35	VBT_outpleakage1 p50 19.e128	P	−10 uA	20 uA	Samples	50	0	−0.000532926 uA	0.0109489 uA	456.7	304.4	100.00 %
36	VBT_outpleakage1 p51 19.g149	P	−10 uA	20 uA	Samples	50	0	0.00123974 uA	0.00942531 uA	530.5	353.7	100.00 %

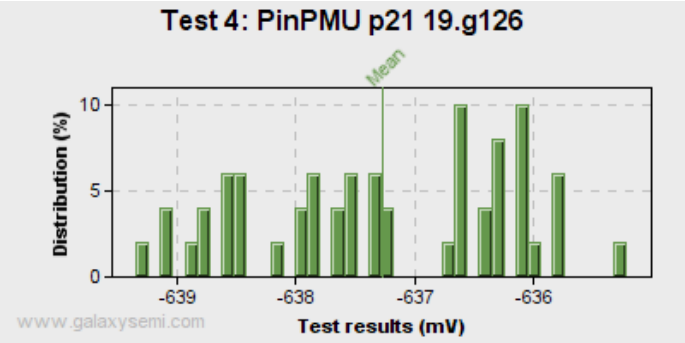
37	VBT_outpleakage1 p52 19.e137	P	−10 uA	20 uA	Samples	50	0	9.18937e−05 uA	0.0083108 uA	601.6	401.1	100.00 %
38	VBT_outpleakage1 p53 19.e135	P	−10 uA	20 uA	Samples	50	0	0.00111211 uA	0.0110484 uA	452.6	301.7	100.00 %
39	VBT_outpleakage1 p60 19.g130	P	−10 uA	20 uA	Samples	50	0	0.000397933 uA	0.0100743 uA	496.3	330.9	100.00 %
40	VBT_outpleakage1 p61 19.g104	P	−10 uA	20 uA	Samples	50	0	0.0035875 uA	0.00879669 uA	568.4	379.1	100.00 %
41	VBT_outpleakage1 p62 19.g102	P	−10 uA	20 uA	Samples	50	0	0.00864791 uA	0.0104522 uA	478.4	319.2	100.00 %
42	VBT_outpleakage1 p63 19.e102	P	−10 uA	20 uA	Samples	50	0	0.00231812 uA	0.0126815 uA	394.3	262.9	100.00 %
43	VBT_outpleakage1 p70 19.g139	P	−10 uA	20 uA	Samples	50	0	0.000792998 uA	0.00970943 uA	515.0	343.3	100.00 %
44	VBT_outpleakage1 p71 19.g147	P	−10 uA	20 uA	Samples	50	0	0.00409511 uA	0.00916034 uA	545.8	364.0	100.00 %
45	VBT_outpleakage1 p72 19.e104	P	−10 uA	20 uA	Samples	50	0	0.00181427 uA	0.0117014 uA	427.3	284.9	100.00 %
46	VBT_outpleakage1 p73 19.e108	P	−10 uA	20 uA	Samples	50	0	0.00609806 uA	0.00858709 uA	582.3	388.4	100.00 %
47	OutputZ_leak_vbt1 p40 19.e130	P	−10 uA	20 uA	Samples	50	0	−0.000122588 uA	0.010324 uA	484.3	322.9	100.00 %
48	OutputZ_leak_vbt1 p41 19.e139	P	−10 uA	20 uA	Samples	50	0	0.00399602 uA	0.0104804 uA	477.1	318.2	100.00 %
49	OutputZ_leak_vbt1 p42 19.e147	P	−10 uA	20 uA	Samples	50	0	0.000273963 uA	0.0105496 uA	474.0	316.0	100.00 %
50	OutputZ_leak_vbt1 p43 19.e151	P	−10 uA	20 uA	Samples	50	0	0.000978549 uA	0.00934048 uA	535.3	356.9	100.00 %
51	OutputZ_leak_vbt1 p50 19.e128	P	−10 uA	20 uA	Samples	50	0	0.000380661 uA	0.00964509 uA	518.4	345.6	100.00 %
52	OutputZ_leak_vbt1 p51 19.g149	P	−10 uA	20 uA	Samples	50	0	−0.000459163 uA	0.00999257 uA	500.4	333.6	100.00 %
53	OutputZ_leak_vbt1 p52 19.e137	P	−10 uA	20 uA	Samples	50	0	0.00220545 uA	0.00873213 uA	572.6	381.8	100.00 %
54	OutputZ_leak_vbt1 p53 19.e135	P	−10 uA	20 uA	Samples	50	0	−0.00172148 uA	0.0089767 uA	557.0	371.3	100.00 %
55	OutputZ_leak_vbt1 p60 19.g130	P	−10 uA	20 uA	Samples	50	0	−0.00134685 uA	0.0102018 uA	490.1	326.7	100.00 %
56	OutputZ_leak_vbt1 p61 19.g104	P	−10 uA	20 uA	Samples	50	0	0.00355697 uA	0.00880853 uA	567.6	378.6	100.00 %
57	OutputZ_leak_vbt1 p62 19.g102	P	−10 uA	20 uA	Samples	50	0	0.00720914 uA	0.0148689 uA	336.3	224.3	100.00 %
58	OutputZ_leak_vbt1 p63 19.e102	P	−10 uA	20 uA	Samples	50	0	0.00268413 uA	0.00922085 uA	542.2	361.6	100.00 %
59	OutputZ_leak_vbt1 p70 19.g139	P	−10 uA	20 uA	Samples	50	0	−0.00398024 uA	0.00998801 uA	500.6	333.6	100.00 %
60	OutputZ_leak_vbt1 p71 19.g147	P	−10 uA	20 uA	Samples	50	0	0.00641107 uA	0.00939431 uA	532.2	355.1	100.00 %
61	OutputZ_leak_vbt1 p72 19.e104	P	−10 uA	20 uA	Samples	50	0	−0.00164656 uA	0.0119793 uA	417.4	278.2	100.00 %
62	OutputZ_leak_vbt1 p73 19.e108	P	−10 uA	20 uA	Samples	50	0	0.00280511 uA	0.00907797 uA	550.8	367.3	100.00 %
63	Functional_T4	F	n/a .	n/a .	Samples	50	0	n/a .	n/a .	n/a .	n/a .	100.00 %
Test	**Name**	**Type**	**Low L.**	**High L.**	**Source**	**Execs**	**Fails**	**Mean**	**Sigma**	**Cp**	**Cpk**	**Yield**
64	icc_static_vbt11 vcc 15.e201 <> Icc_static	P	10 uA	500 uA	Samples	50	0	21.2196 uA	0.243143 uA	335.9	15.38	100.00 %
65	Icc_dynamic vcc 15.e201 <> Icc_dynamic	P	10 uA	500 uA	Samples	50	0	20.7699 uA	0.320798 uA	254.6	11.19	100.00 %
67	Functional_T5 p50 19.e128	P	0 m	500 m	Samples	50	0	144.88 m	2.30031 m	36.23	20.99	100.00 %
68	Functional_T5 p50 19.e128	P	2.8	3.4	Samples	50	0	3.28374	0.00206834	48.35	18.74	100.00 %
70	Functional_T6 A8 0	P	1 ns	100 ns	Samples	50	0	10.96 ns	3.0836 ns	5.35	1.08	100.00 %
71	Functional_T7 p53 19.e135	P	2.5 V	3.5 V	Samples	50	0	3.28292 V	0.00230213 V	72.40	31.43	100.00 %
72	Functional_T7 p53 19.e135	P	0 m	500 m	Samples	50	0	139 m	2.35606 m	35.37	19.67	100.00 %
74	Functional_T8 A8 0	P	1 ns	100 ns	Samples	50	31	1700.48 ns	1752.32 ns	0.0094	−0.3044	38.00 %
786000	Soft_Bin parameter	–	n/a .	n/a .	Samples	50	0	1	0	n/a .	n/a .	100.00 %
786001	Hard_Bin parameter	–	n/a .	n/a .	Samples	50	0	1	0	n/a .	n/a .	100.00 %
786002	Die_X parameter	–	n/a .	n/a .	Samples	50	0	2.94	2.0445	n/a .	n/a .	100.00 %
786003	Die_Y parameter	–	n/a .	n/a .	Samples	50	0	3.92	2.07846	n/a .	n/a .	100.00 %
786004	Test_Time parameter	–	0.0 sec	n/a .	Samples	50	0	2.70458 sec	0.0934858 sec	n/a .	9.64	100.00 %
786006	Testing_Site parameter	–	n/a .	n/a .	Samples	50	0	0	0	n/a .	n/a .	100.00 %
786007	Part_ID parameter	–	n/a .	n/a .	Samples	50	0	25.5	14.5774	n/a .	n/a .	100.00 %

Histogram of Tests

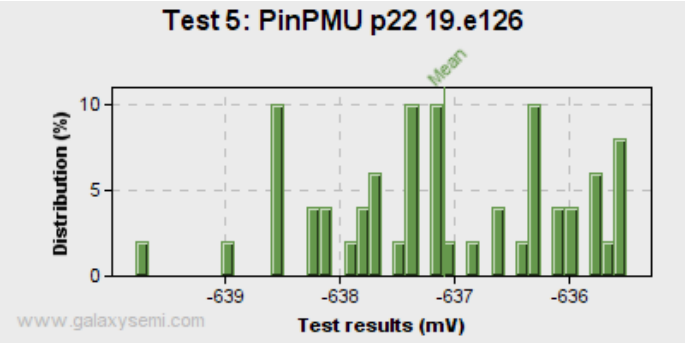
Test	3
Name	PinPMU p20 19.g128
Test type	Parametric
Low limit	−1200 mV
High limit	−100 mV
Exec / Fails	50 / 0 (0.00%)
Mean	−637.161 mV
Sigma	1.09672 mV
Range	3.96818 mV
Cp / Cpk	167.2 / 163.3
Samples	50



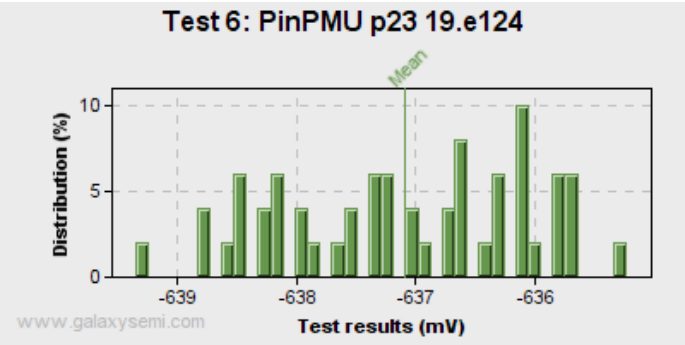
Test	4
Name	PinPMU p21 19.g126
Test type	Parametric
Low limit	−1200 mV
High limit	−100 mV
Exec / Fails	50 / 0 (0.00%)
Mean	−637.269 mV
Sigma	1.06833 mV
Range	4.12124 mV
Cp / Cpk	171.6 / 167.6
Samples	50



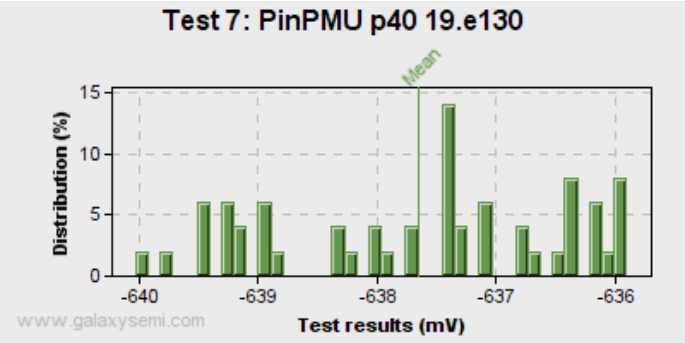
Test	5
Name	PinPMU p22 19.e126
Test type	Parametric
Low limit	−1200 mV
High limit	−100 mV
Exec / Fails	50 / 0 (0.00%)
Mean	−637.096 mV
Sigma	1.06354 mV
Range	4.27264 mV
Cp / Cpk	172.4 / 168.3
Samples	50



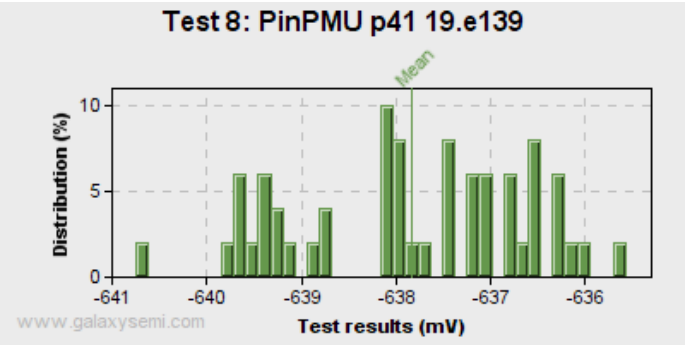
Test	6
Name	PinPMU p23 19.e124
Test type	Parametric
Low limit	−1200 mV
High limit	−100 mV
Exec / Fails	50 / 0 (0.00%)
Mean	−637.092 mV
Sigma	1.01629 mV
Range	4.12089 mV
Cp / Cpk	180.4 / 176.2
Samples	50



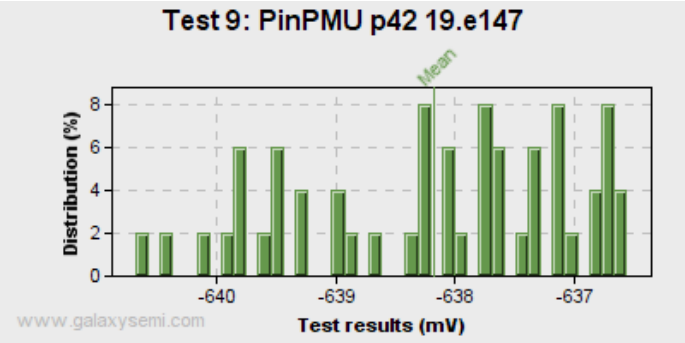
Test	7
Name	PinPMU p40 19.e130
Test type	Parametric
Low limit	−1200 mV
High limit	−100 mV
Exec / Fails	50 / 0 (0.00%)
Mean	−637.646 mV
Sigma	1.2127 mV
Range	4.12035 mV
Cp / Cpk	151.2 / 147.8
Samples	50



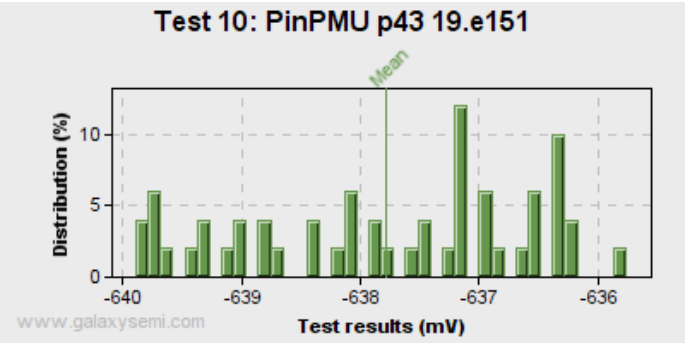
Test	8
Name	PinPMU p41 19.e139
Test type	Parametric
Low limit	−1200 mV
High limit	−100 mV
Exec / Fails	50 / 0 (0.00%)
Mean	−637.829 mV
Sigma	1.2408 mV
Range	5.1893 mV
Cp / Cpk	147.8 / 144.5
Samples	50



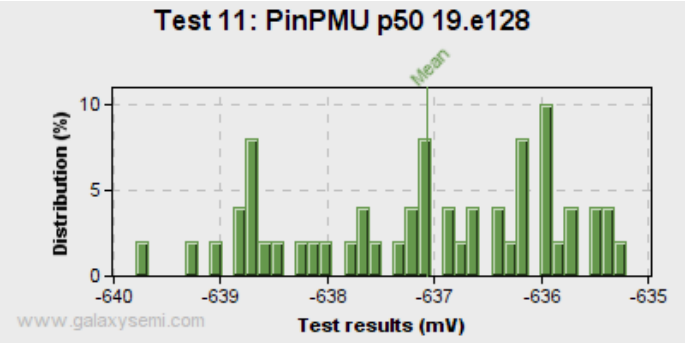
Test	9
Name	PinPMU p42 19.e147
Test type	Parametric
Low limit	−1200 mV
High limit	−100 mV
Exec / Fails	50 / 0 (0.00%)
Mean	−638.176 mV
Sigma	1.14196 mV
Range	4.12023 mV
Cp / Cpk	160.5 / 157.1
Samples	50



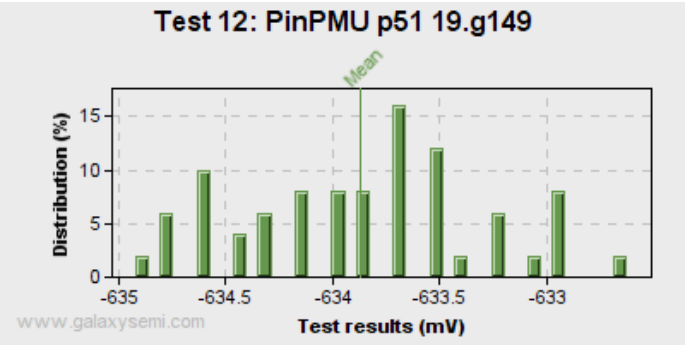
Test	10
Name	PinPMU p43 19.e151
Test type	Parametric
Low limit	−1200 mV
High limit	−100 mV
Exec / Fails	50 / 0 (0.00%)
Mean	−637.78 mV
Sigma	1.19472 mV
Range	4.12315 mV
Cp / Cpk	153.5 / 150.0
Samples	50



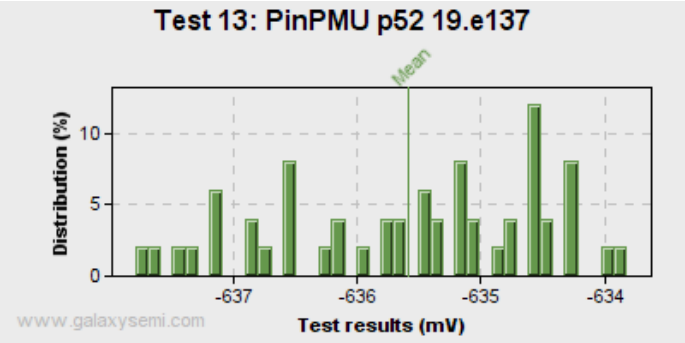
Test	11
Name	PinPMU p50 19.e128
Test type	Parametric
Low limit	−1200 mV
High limit	−100 mV
Exec / Fails	50 / 0 (0.00%)
Mean	−637.068 mV
Sigma	1.2283 mV
Range	4.58056 mV
Cp / Cpk	149.3 / 145.7
Samples	50



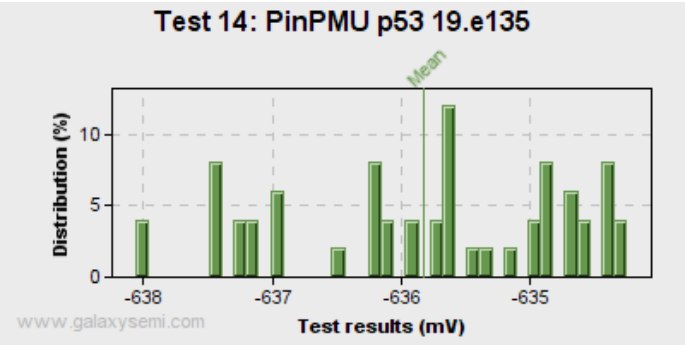
Test	12
Name	PinPMU p51 19.g149
Test type	Parametric
Low limit	−1200 mV
High limit	−100 mV
Exec / Fails	50 / 0 (0.00%)
Mean	−633.867 mV
Sigma	0.569337 mV
Range	2.28912 mV
Cp / Cpk	322.0 / 312.6
Samples	50



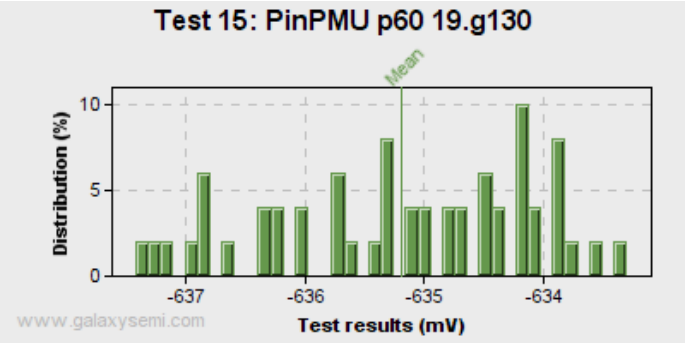
Test	13
Name	PinPMU p52 19.e137
Test type	Parametric
Low limit	−1200 mV
High limit	−100 mV
Exec / Fails	50 / 0 (0.00%)
Mean	−635.589 mV
Sigma	1.08386 mV
Range	3.96913 mV
Cp / Cpk	169.1 / 164.7
Samples	50



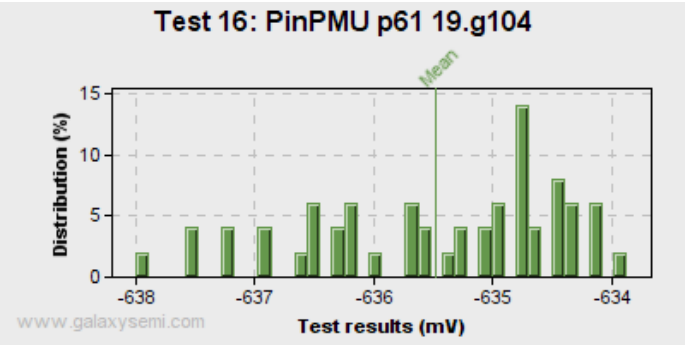
Test	14
Name	PinPMU p53 19.e135
Test type	Parametric
Low limit	−1200 mV
High limit	−100 mV
Exec / Fails	50 / 0 (0.00%)
Mean	−635.818 mV
Sigma	1.10748 mV
Range	3.8147 mV
Cp / Cpk	165.5 / 161.3
Samples	50



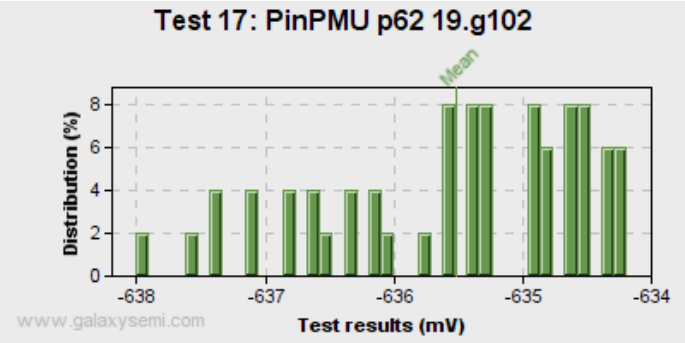
Test	15
Name	PinPMU p60 19.g130
Test type	Parametric
Low limit	−1200 mV
High limit	−100 mV
Exec / Fails	50 / 0 (0.00%)
Mean	−635.187 mV
Sigma	1.09843 mV
Range	4.12107 mV
Cp / Cpk	166.9 / 162.4
Samples	50



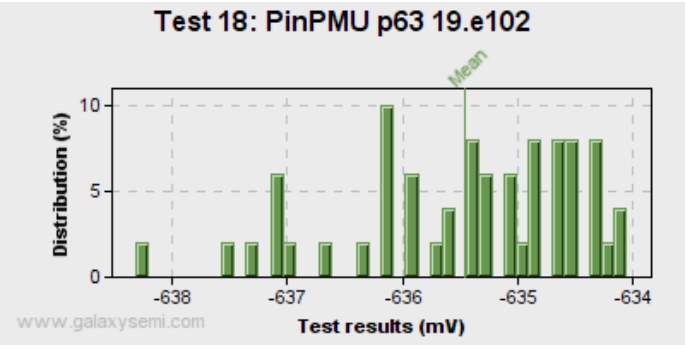
Test	16
Name	PinPMU p61 19.g104
Test type	Parametric
Low limit	−1200 mV
High limit	−100 mV
Exec / Fails	50 / 0 (0.00%)
Mean	−635.473 mV
Sigma	1.05163 mV
Range	4.12071 mV
Cp / Cpk	174.3 / 169.7
Samples	50



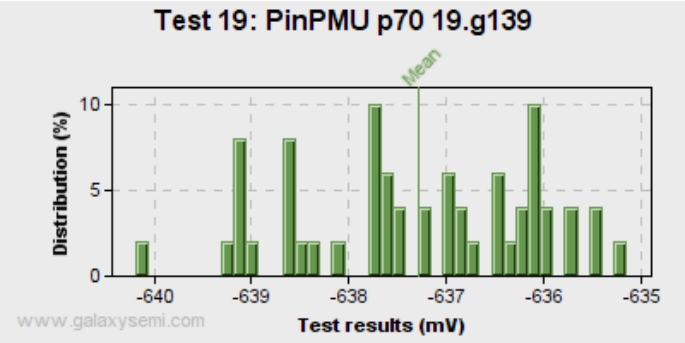
Test	17
Name	PinPMU p62 19.g102
Test type	Parametric
Low limit	−1200 mV
High limit	−100 mV
Exec / Fails	50 / 0 (0.00%)
Mean	−635.515 mV
Sigma	1.02179 mV
Range	3.81535 mV
Cp / Cpk	179.4 / 174.7
Samples	50



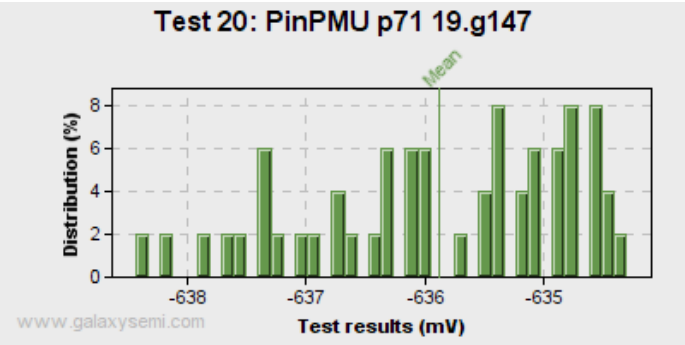
Test	18
Name	PinPMU p63 19.e102
Test type	Parametric
Low limit	−1200 mV
High limit	−100 mV
Exec / Fails	50 / 0 (0.00%)
Mean	−635.459 mV
Sigma	1.0159 mV
Range	4.27234 mV
Cp / Cpk	180.5 / 175.7
Samples	50



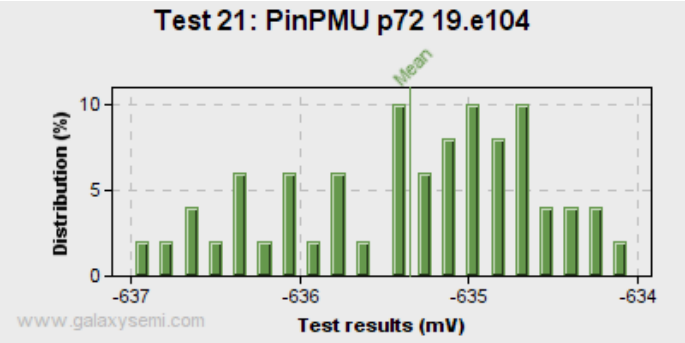
Test	19
Name	PinPMU p70 19.g139
Test type	Parametric
Low limit	−1200 mV
High limit	−100 mV
Exec / Fails	50 / 0 (0.00%)
Mean	−637.288 mV
Sigma	1.22761 mV
Range	5.03761 mV
Cp / Cpk	149.3 / 145.9
Samples	50



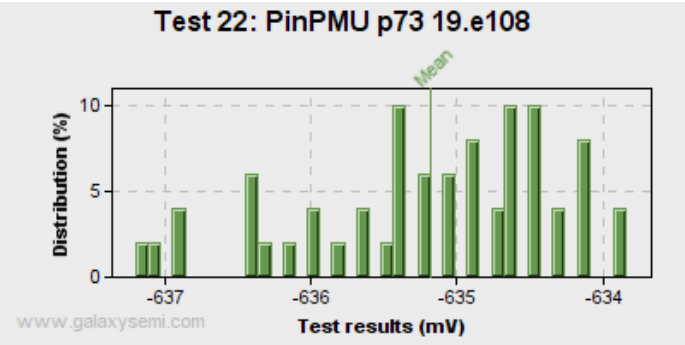
Test	20
Name	PinPMU p71 19.g147
Test type	Parametric
Low limit	−1200 mV
High limit	−100 mV
Exec / Fails	50 / 0 (0.00%)
Mean	−635.878 mV
Sigma	1.10474 mV
Range	4.12142 mV
Cp / Cpk	166.0 / 161.7
Samples	50



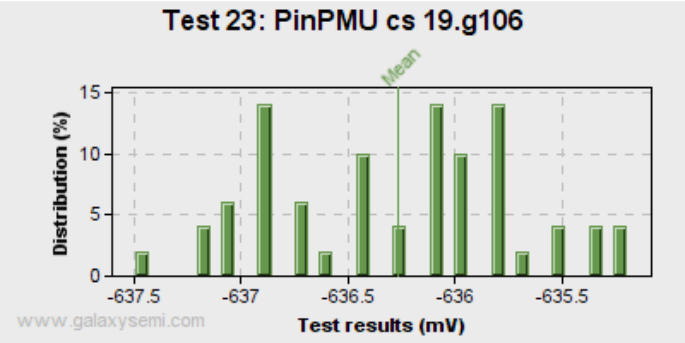
Test	21
Name	PinPMU p72 19.e104
Test type	Parametric
Low limit	−1200 mV
High limit	−100 mV
Exec / Fails	50 / 0 (0.00%)
Mean	−635.343 mV
Sigma	0.747199 mV
Range	2.90066 mV
Cp / Cpk	245.4 / 238.8
Samples	50



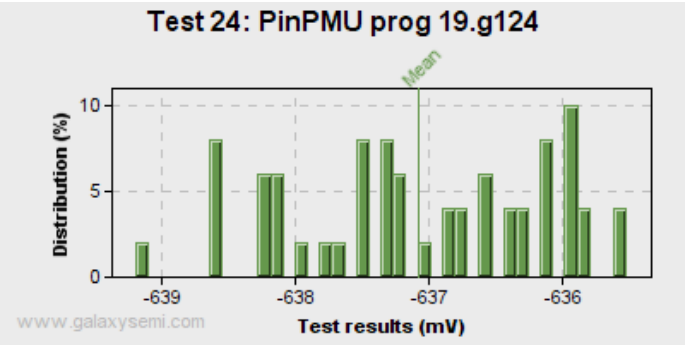
Test	22
Name	PinPMU p73 19.e108
Test type	Parametric
Low limit	−1200 mV
High limit	−100 mV
Exec / Fails	50 / 0 (0.00%)
Mean	−635.181 mV
Sigma	0.87077 mV
Range	3.35735 mV
Cp / Cpk	210.5 / 204.9
Samples	50



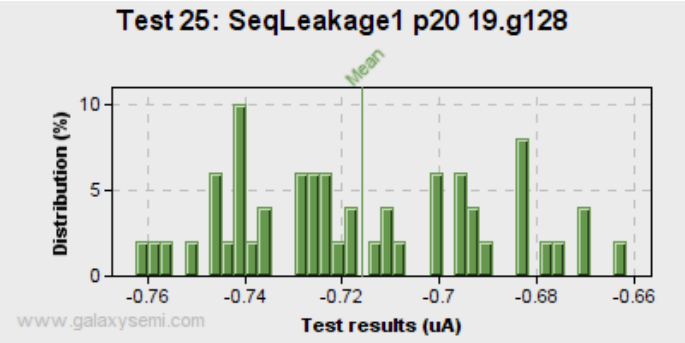
Test	23
Name	PinPMU cs 19.g106
Test type	Parametric
Low limit	−1200 mV
High limit	−100 mV
Exec / Fails	50 / 0 (0.00%)
Mean	−636.27 mV
Sigma	0.57071 mV
Range	2.28959 mV
Cp / Cpk	321.2 / 313.2
Samples	50



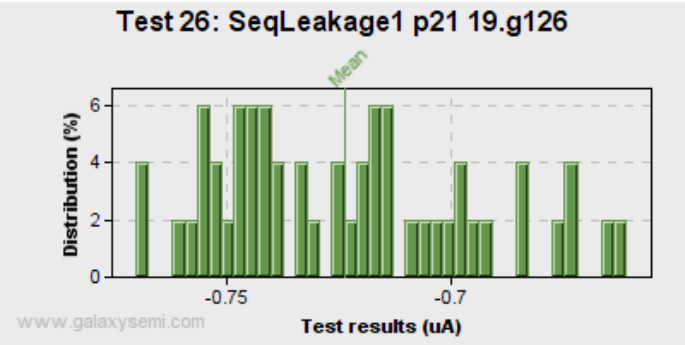
Test	24
Name	PinPMU prog 19.g124
Test type	Parametric
Low limit	−1200 mV
High limit	−100 mV
Exec / Fails	50 / 0 (0.00%)
Mean	−637.077 mV
Sigma	0.950625 mV
Range	3.66259 mV
Cp / Cpk	192.9 / 188.3
Samples	50



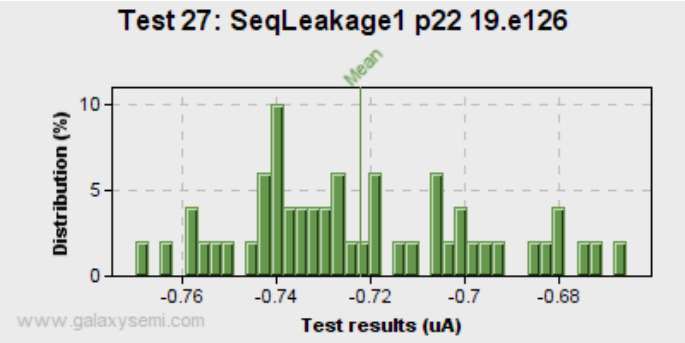
Test	25
Name	SeqLeakage1 p20 19.g128
Test type	Parametric
Low limit	–30 uA
High limit	10 uA
Exec / Fails	50 / 0 (0.00%)
Mean	–0.715957 uA
Sigma	0.0262825 uA
Range	0.100624 uA
Cp / Cpk	253.7 / 135.9
Samples	50



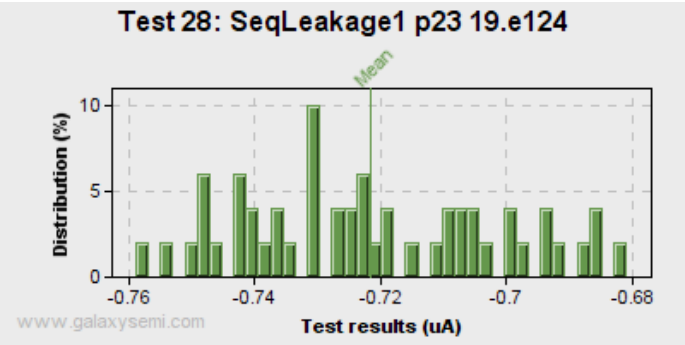
Test	26
Name	SeqLeakage1 p21 19.g126
Test type	Parametric
Low limit	–30 uA
High limit	10 uA
Exec / Fails	50 / 0 (0.00%)
Mean	–0.72361 uA
Sigma	0.0284521 uA
Range	0.109485 uA
Cp / Cpk	234.3 / 125.6
Samples	50



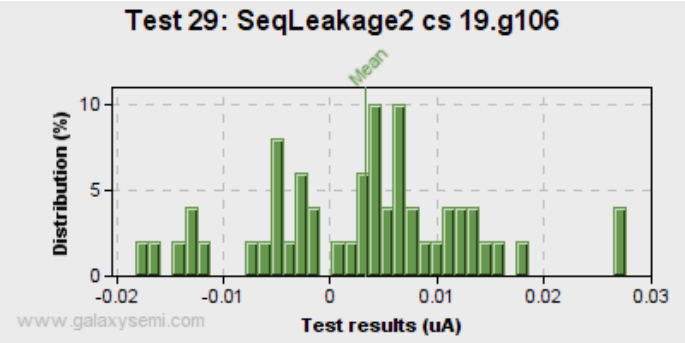
Test	27
Name	SeqLeakage1 p22 19.e126
Test type	Parametric
Low limit	–30 uA
High limit	10 uA
Exec / Fails	50 / 0 (0.00%)
Mean	–0.722307 uA
Sigma	0.0258041 uA
Range	0.104094 uA
Cp / Cpk	258.4 / 138.5
Samples	50



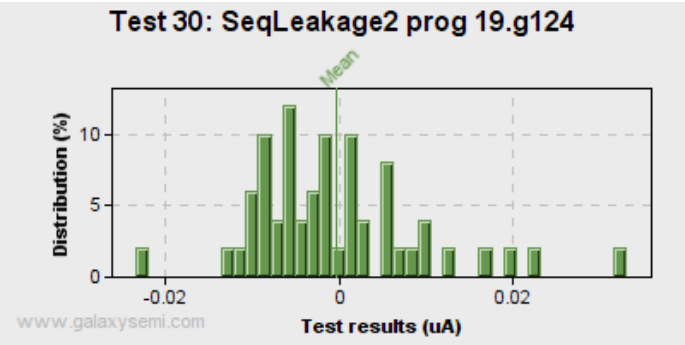
Test	28
Name	SeqLeakage1 p23 19.e124
Test type	Parametric
Low limit	–30 uA
High limit	10 uA
Exec / Fails	50 / 0 (0.00%)
Mean	–0.721546 uA
Sigma	0.0204089 uA
Range	0.0778202 uA
Cp / Cpk	326.7 / 175.1
Samples	50



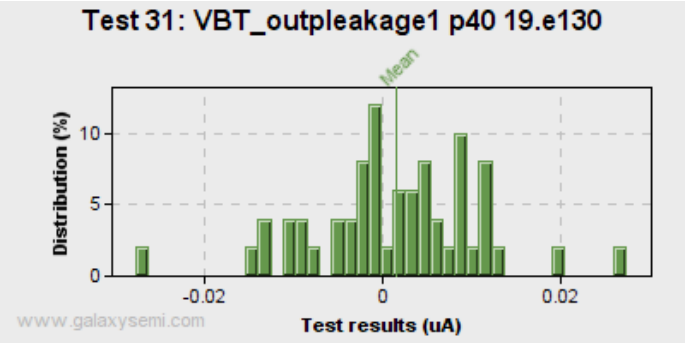
Test	29
Name	SeqLeakage2 cs 19.g106
Test type	Parametric
Low limit	−30 uA
High limit	10 uA
Exec / Fails	50 / 0 (0.00%)
Mean	0.0033208 uA
Sigma	0.00999079 uA
Range	0.0459096 uA
Cp / Cpk	667.3 / 333.5
Samples	50



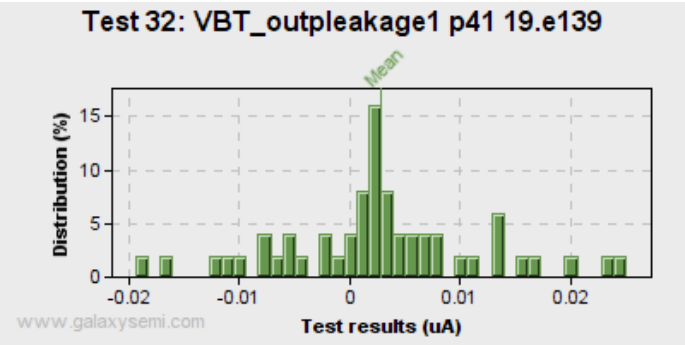
Test	30
Name	SeqLeakage2 prog 19.g124
Test type	Parametric
Low limit	−30 uA
High limit	10 uA
Exec / Fails	50 / 0 (0.00%)
Mean	−0.000305603 uA
Sigma	0.00986529 uA
Range	0.0565365 uA
Cp / Cpk	675.8 / 337.9
Samples	50



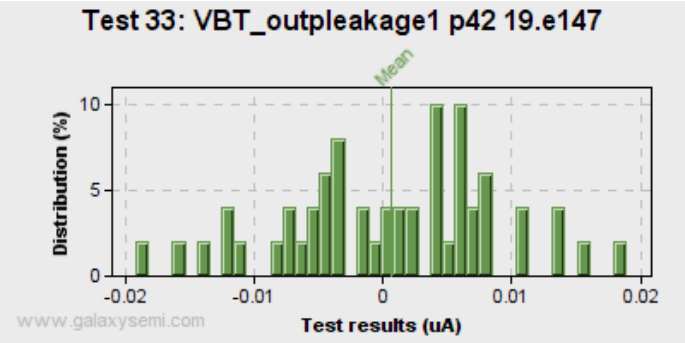
Test	31
Name	VBT_outpleakage1 p40 19.e130
Test type	Parametric
Low limit	−10 uA
High limit	20 uA
Exec / Fails	50 / 0 (0.00%)
Mean	0.00150171 uA
Sigma	0.00942499 uA
Range	0.0551647 uA
Cp / Cpk	530.5 / 353.7
Samples	50



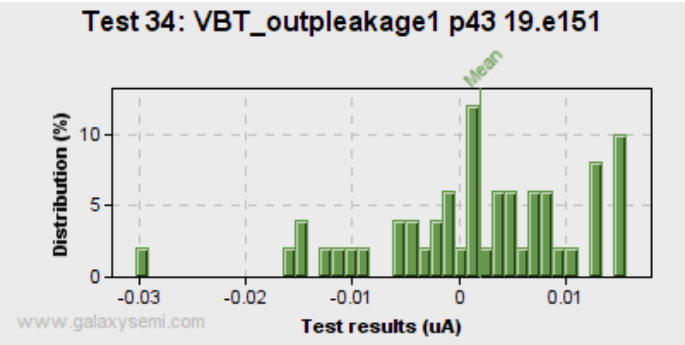
Test	32
Name	VBT_outpleakage1 p41 19.e139
Test type	Parametric
Low limit	−10 uA
High limit	20 uA
Exec / Fails	50 / 0 (0.00%)
Mean	0.00289367 uA
Sigma	0.00922327 uA
Range	0.0444002 uA
Cp / Cpk	542.1 / 361.5
Samples	50



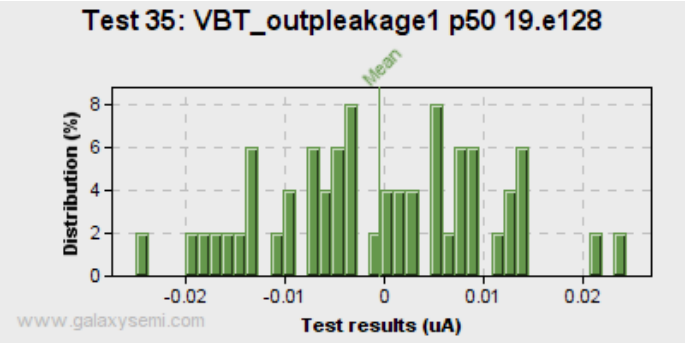
Test	33
Name	VBT_outpleakage1 p42 19.e147
Test type	Parametric
Low limit	−10 uA
High limit	20 uA
Exec / Fails	50 / 0 (0.00%)
Mean	0.000700129 uA
Sigma	0.0082731 uA
Range	0.0380505 uA
Cp / Cpk	604.4 / 402.9
Samples	50



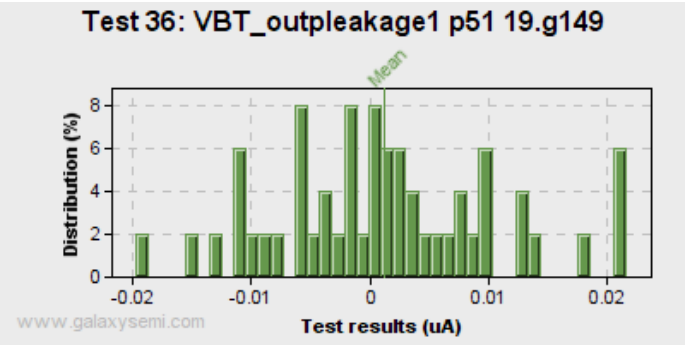
Test	34
Name	VBT_outpleakage1 p43 19.e151
Test type	Parametric
Low limit	−10 uA
High limit	20 uA
Exec / Fails	50 / 0 (0.00%)
Mean	0.00194181 uA
Sigma	0.00967502 uA
Range	0.0458695 uA
Cp / Cpk	516.8 / 344.6
Samples	50



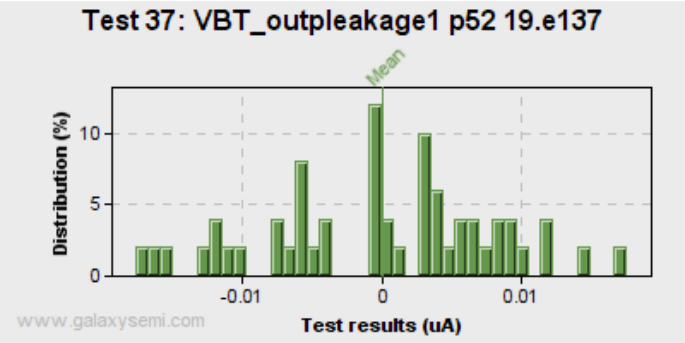
Test	35
Name	VBT_outpleakage1 p50 19.e128
Test type	Parametric
Low limit	−10 uA
High limit	20 uA
Exec / Fails	50 / 0 (0.00%)
Mean	−0.000532926 uA
Sigma	0.0109489 uA
Range	0.049486 uA
Cp / Cpk	456.7 / 304.4
Samples	50



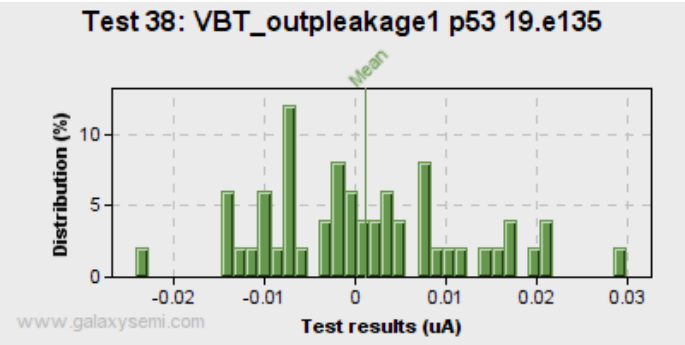
Test	36
Name	VBT_outpleakage1 p51 19.g149
Test type	Parametric
Low limit	−10 uA
High limit	20 uA
Exec / Fails	50 / 0 (0.00%)
Mean	0.00123974 uA
Sigma	0.00942531 uA
Range	0.0413246 uA
Cp / Cpk	530.5 / 353.7
Samples	50



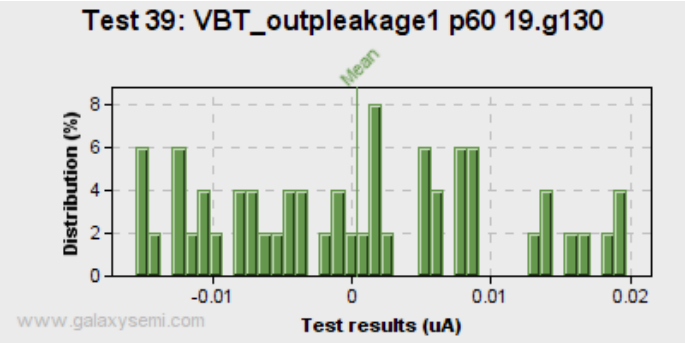
Test	37
Name	VBT_outpleakage1 p52 19.e137
Test type	Parametric
Low limit	−10 uA
High limit	20 uA
Exec / Fails	50 / 0 (0.00%)
Mean	9.18937e−05 uA
Sigma	0.0083108 uA
Range	0.0352259 uA
Cp / Cpk	601.6 / 401.1
Samples	50



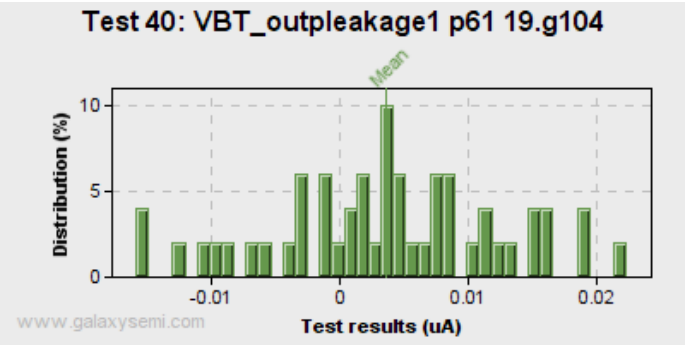
Test	38
Name	VBT_outpleakage1 p53 19.e135
Test type	Parametric
Low limit	−10 uA
High limit	20 uA
Exec / Fails	50 / 0 (0.00%)
Mean	0.00111211 uA
Sigma	0.0110484 uA
Range	0.0540819 uA
Cp / Cpk	452.6 / 301.7
Samples	50



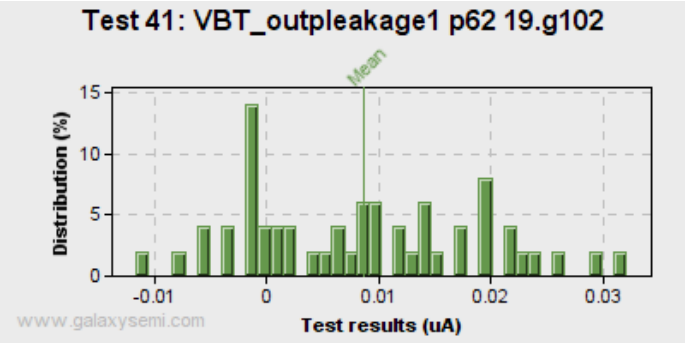
Test	39
Name	VBT_outpleakage1 p60 19.g130
Test type	Parametric
Low limit	−10 uA
High limit	20 uA
Exec / Fails	50 / 0 (0.00%)
Mean	0.000397933 uA
Sigma	0.0100743 uA
Range	0.0352017 uA
Cp / Cpk	496.3 / 330.9
Samples	50



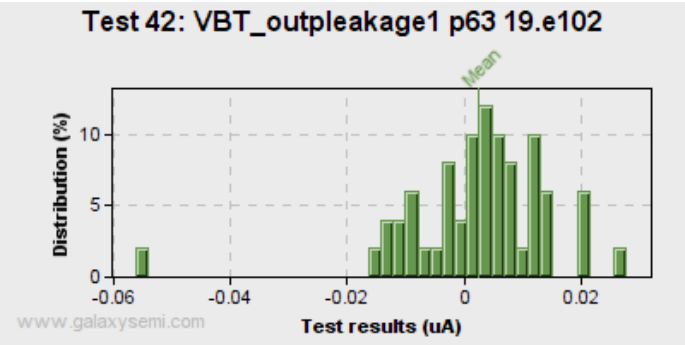
Test	40
Name	VBT_outpleakage1 p61 19.g104
Test type	Parametric
Low limit	−10 uA
High limit	20 uA
Exec / Fails	50 / 0 (0.00%)
Mean	0.0035875 uA
Sigma	0.00879669 uA
Range	0.0381649 uA
Cp / Cpk	568.4 / 379.1
Samples	50



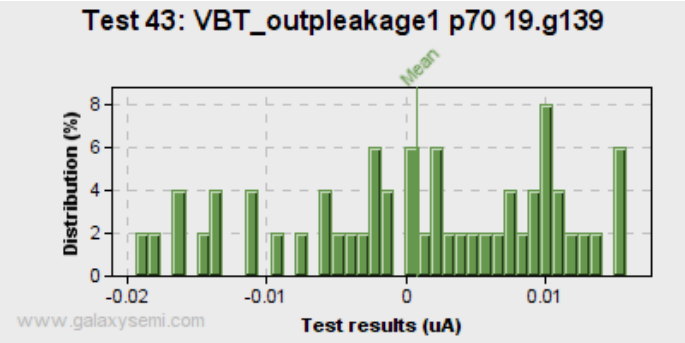
Test	41
Name	VBT_outpleakage1 p62 19.g102
Test type	Parametric
Low limit	−10 uA
High limit	20 uA
Exec / Fails	50 / 0 (0.00%)
Mean	0.00864791 uA
Sigma	0.0104522 uA
Range	0.0436222 uA
Cp / Cpk	478.4 / 319.2
Samples	50



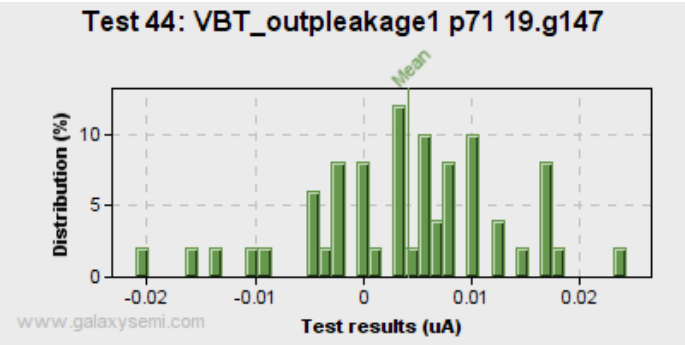
Test	42
Name	VBT_outpleakage1 p63 19.e102
Test type	Parametric
Low limit	−10 uA
High limit	20 uA
Exec / Fails	50 / 0 (0.00%)
Mean	0.00231812 uA
Sigma	0.0126815 uA
Range	0.0838792 uA
Cp / Cpk	394.3 / 262.9
Samples	50



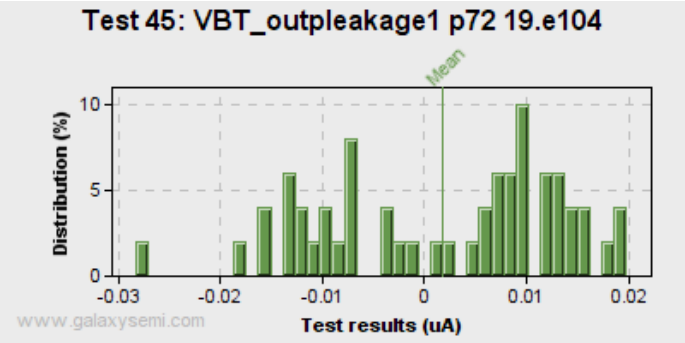
Test	43
Name	VBT_outpleakage1 p70 19.g139
Test type	Parametric
Low limit	−10 uA
High limit	20 uA
Exec / Fails	50 / 0 (0.00%)
Mean	0.000792998 uA
Sigma	0.00970943 uA
Range	0.0350749 uA
Cp / Cpk	515.0 / 343.3
Samples	50



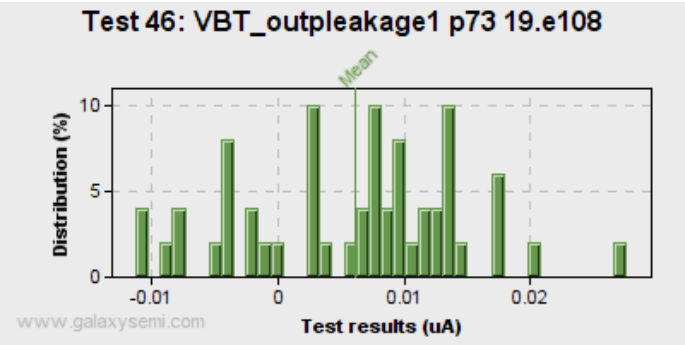
Test	44
Name	VBT_outpleakage1 p71 19.g147
Test type	Parametric
Low limit	−10 uA
High limit	20 uA
Exec / Fails	50 / 0 (0.00%)
Mean	0.00409511 uA
Sigma	0.00916034 uA
Range	0.0452456 uA
Cp / Cpk	545.8 / 364.0
Samples	50



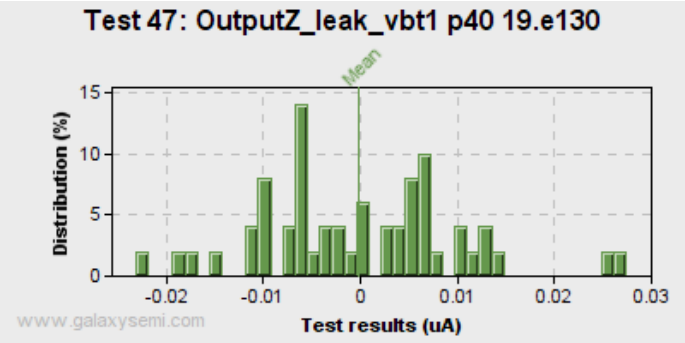
Test	45
Name	VBT_outpleakage1 p72 19.e104
Test type	Parametric
Low limit	−10 uA
High limit	20 uA
Exec / Fails	50 / 0 (0.00%)
Mean	0.00181427 uA
Sigma	0.0117014 uA
Range	0.0480248 uA
Cp / Cpk	427.3 / 284.9
Samples	50



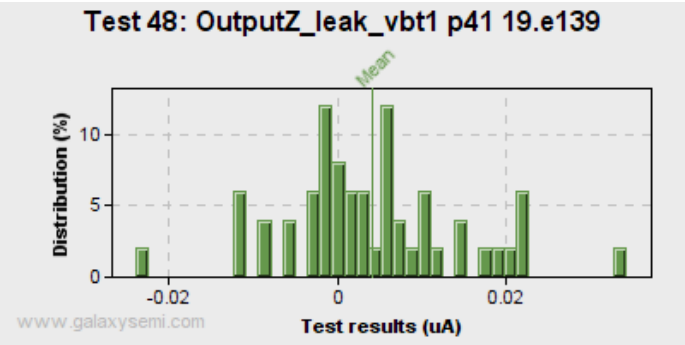
Test	46
Name	VBT_outpleakage1 p73 19.e108
Test type	Parametric
Low limit	−10 uA
High limit	20 uA
Exec / Fails	50 / 0 (0.00%)
Mean	0.00609806 uA
Sigma	0.00858709 uA
Range	0.0388751 uA
Cp / Cpk	582.3 / 388.4
Samples	50



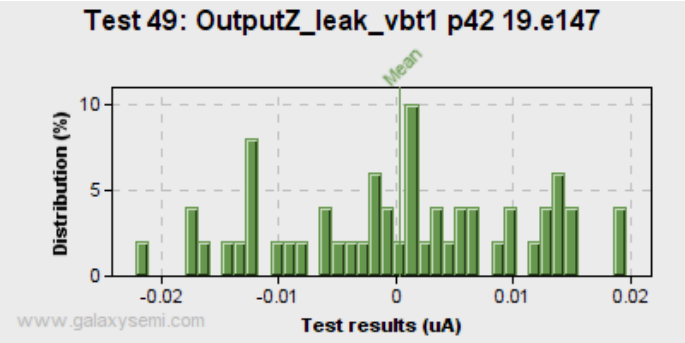
Test	47
Name	OutputZ_leak_vbt1 p40 19.e130
Test type	Parametric
Low limit	−10 uA
High limit	20 uA
Exec / Fails	50 / 0 (0.00%)
Mean	−0.000122588 uA
Sigma	0.010324 uA
Range	0.0505676 uA
Cp / Cpk	484.3 / 322.9
Samples	50



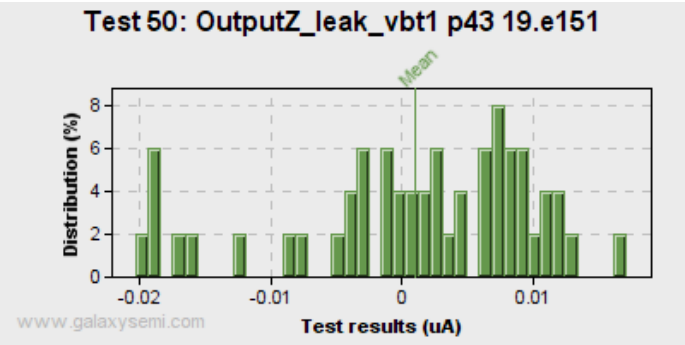
Test	48
Name	OutputZ_leak_vbt1 p41 19.e139
Test type	Parametric
Low limit	−10 uA
High limit	20 uA
Exec / Fails	50 / 0 (0.00%)
Mean	0.00399602 uA
Sigma	0.0104804 uA
Range	0.0581796 uA
Cp / Cpk	477.1 / 318.2
Samples	50



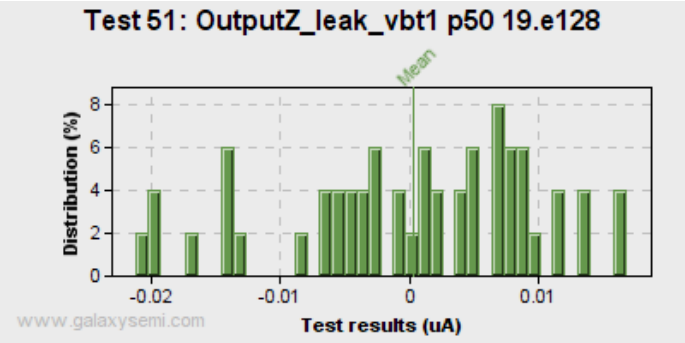
Test	49
Name	OutputZ_leak_vbt1 p42 19.e147
Test type	Parametric
Low limit	−10 uA
High limit	20 uA
Exec / Fails	50 / 0 (0.00%)
Mean	0.000273963 uA
Sigma	0.0105496 uA
Range	0.0418555 uA
Cp / Cpk	474.0 / 316.0
Samples	50



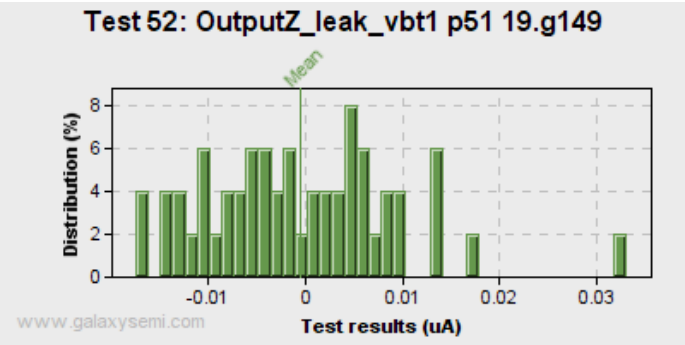
Test	50
Name	OutputZ_leak_vbt1 p43 19.e151
Test type	Parametric
Low limit	−10 uA
High limit	20 uA
Exec / Fails	50 / 0 (0.00%)
Mean	0.000978549 uA
Sigma	0.00934048 uA
Range	0.0374601 uA
Cp / Cpk	535.3 / 356.9
Samples	50



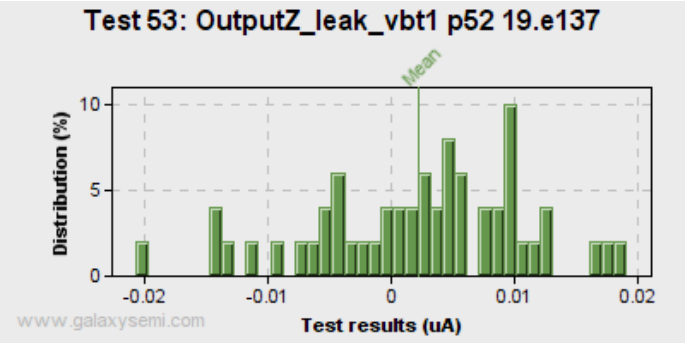
Test	51
Name	OutputZ_leak_vbt1 p50 19.e128
Test type	Parametric
Low limit	−10 uA
High limit	20 uA
Exec / Fails	50 / 0 (0.00%)
Mean	0.000380661 uA
Sigma	0.00964509 uA
Range	0.0380661 uA
Cp / Cpk	518.4 / 345.6
Samples	50



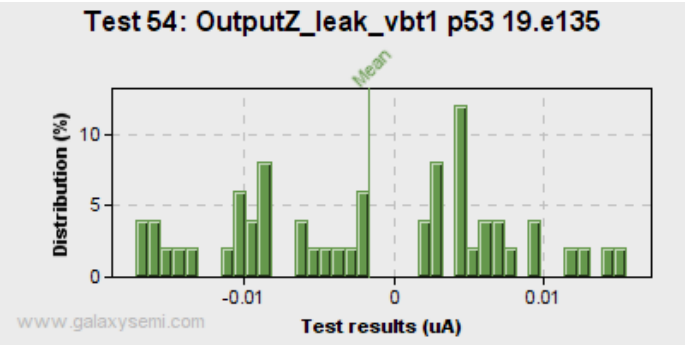
Test	52
Name	OutputZ_leak_vbt1 p51 19.g149
Test type	Parametric
Low limit	−10 uA
High limit	20 uA
Exec / Fails	50 / 0 (0.00%)
Mean	−0.000459163 uA
Sigma	0.00999257 uA
Range	0.0505079 uA
Cp / Cpk	500.4 / 333.6
Samples	50



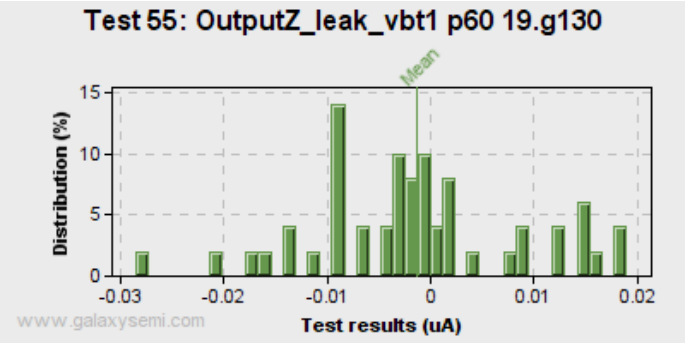
Test	53
Name	OutputZ_leak_vbt1 p52 19.e137
Test type	Parametric
Low limit	−10 uA
High limit	20 uA
Exec / Fails	50 / 0 (0.00%)
Mean	0.00220545 uA
Sigma	0.00873213 uA
Range	0.0398206 uA
Cp / Cpk	572.6 / 381.8
Samples	50



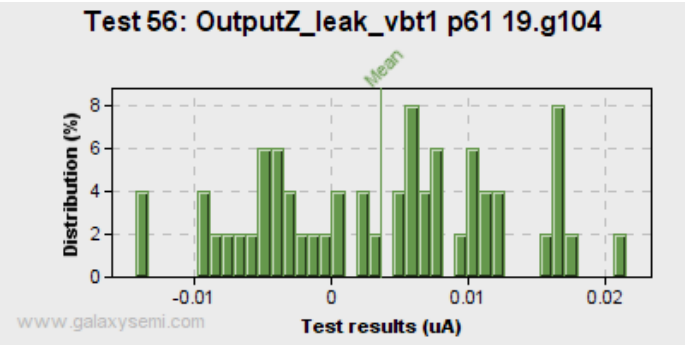
Test	54
Name	OutputZ_leak_vbt1 p53 19.e135
Test type	Parametric
Low limit	−10 uA
High limit	20 uA
Exec / Fails	50 / 0 (0.00%)
Mean	−0.00172148 uA
Sigma	0.0089767 uA
Range	0.0327538 uA
Cp / Cpk	557.0 / 371.3
Samples	50



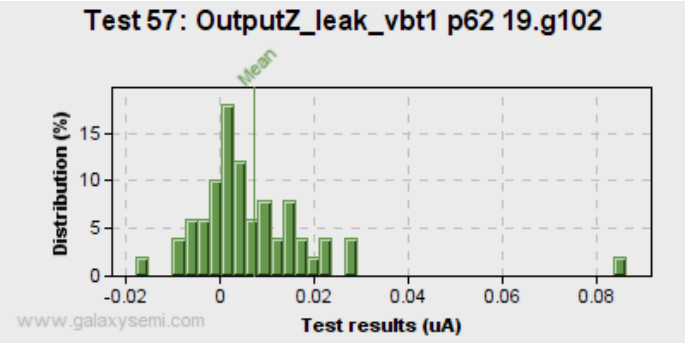
Test	55
Name	OutputZ_leak_vbt1 p60 19.g130
Test type	Parametric
Low limit	−10 uA
High limit	20 uA
Exec / Fails	50 / 0 (0.00%)
Mean	−0.00134685 uA
Sigma	0.0102018 uA
Range	0.0474458 uA
Cp / Cpk	490.1 / 326.7
Samples	50



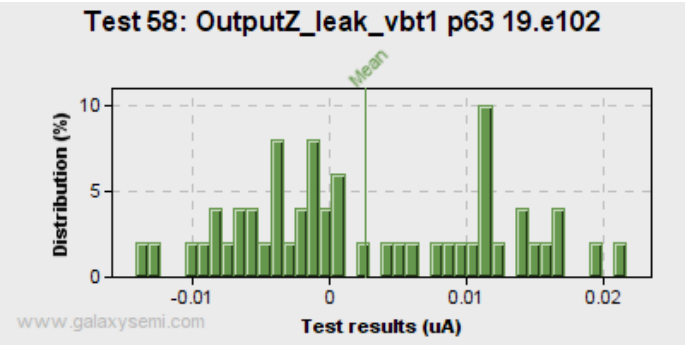
Test	56
Name	OutputZ_leak_vbt1 p61 19.g104
Test type	Parametric
Low limit	−10 uA
High limit	20 uA
Exec / Fails	50 / 0 (0.00%)
Mean	0.00355697 uA
Sigma	0.00880853 uA
Range	0.035875 uA
Cp / Cpk	567.6 / 378.6
Samples	50



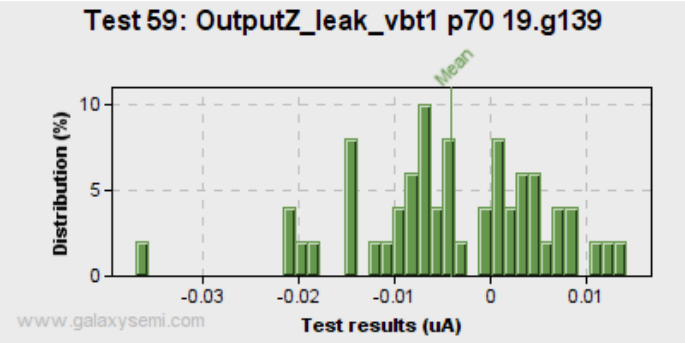
Test	57
Name	OutputZ_leak_vbt1 p62 19.g102
Test type	Parametric
Low limit	−10 uA
High limit	20 uA
Exec / Fails	50 / 0 (0.00%)
Mean	0.00720914 uA
Sigma	0.0148689 uA
Range	0.104081 uA
Cp / Cpk	336.3 / 224.3
Samples	50



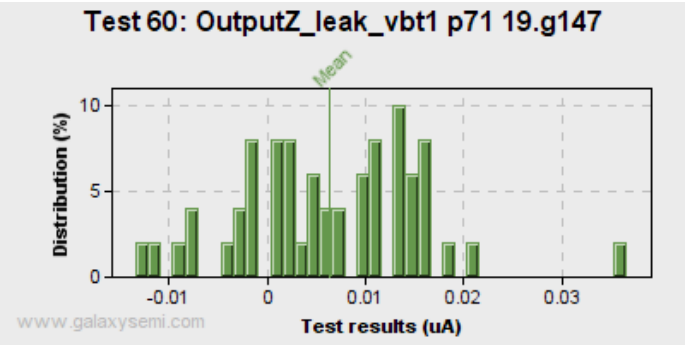
Test	58
Name	OutputZ_leak_vbt1 p63 19.e102
Test type	Parametric
Low limit	−10 uA
High limit	20 uA
Exec / Fails	50 / 0 (0.00%)
Mean	0.00268413 uA
Sigma	0.00922085 uA
Range	0.0358393 uA
Cp / Cpk	542.2 / 361.6
Samples	50



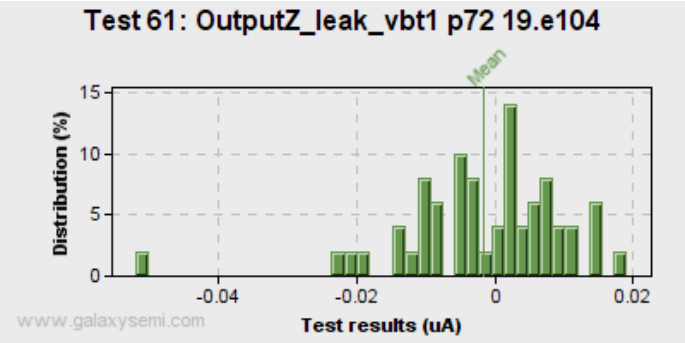
Test	59
Name	OutputZ_leak_vbt1 p70 19.g139
Test type	Parametric
Low limit	−10 uA
High limit	20 uA
Exec / Fails	50 / 0 (0.00%)
Mean	−0.00398024 uA
Sigma	0.00998801 uA
Range	0.0510874 uA
Cp / Cpk	500.6 / 333.6
Samples	50



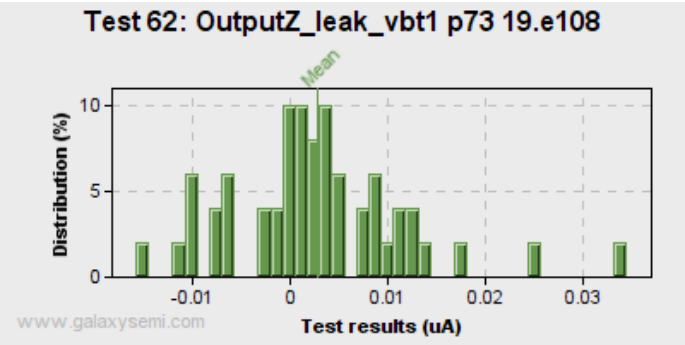
Test	60
Name	OutputZ_leak_vbt1 p71 19.g147
Test type	Parametric
Low limit	−10 uA
High limit	20 uA
Exec / Fails	50 / 0 (0.00%)
Mean	0.00641107 uA
Sigma	0.00939431 uA
Range	0.0498468 uA
Cp / Cpk	532.2 / 355.1
Samples	50



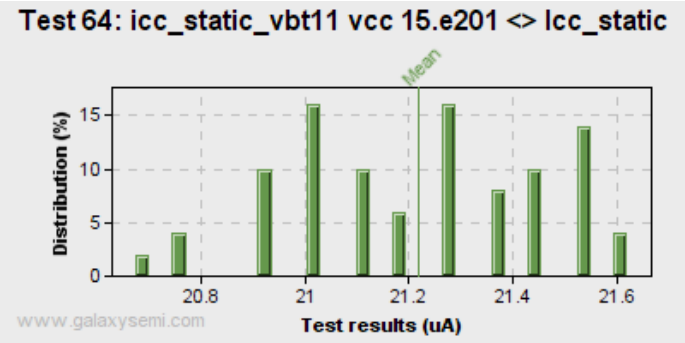
Test	61
Name	OutputZ_leak_vbt1 p72 19.e104
Test type	Parametric
Low limit	−10 uA
High limit	20 uA
Exec / Fails	50 / 0 (0.00%)
Mean	−0.00164656 uA
Sigma	0.0119793 uA
Range	0.0708937 uA
Cp / Cpk	417.4 / 278.2
Samples	50



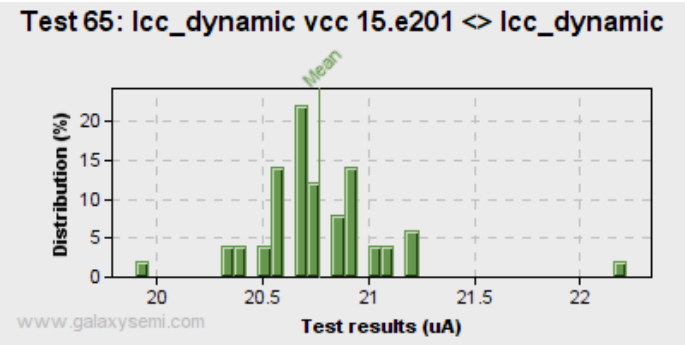
Test	62
Name	OutputZ_leak_vbt1 p73 19.e108
Test type	Parametric
Low limit	−10 uA
High limit	20 uA
Exec / Fails	50 / 0 (0.00%)
Mean	0.00280511 uA
Sigma	0.00907797 uA
Range	0.050309 uA
Cp / Cpk	550.8 / 367.3
Samples	50



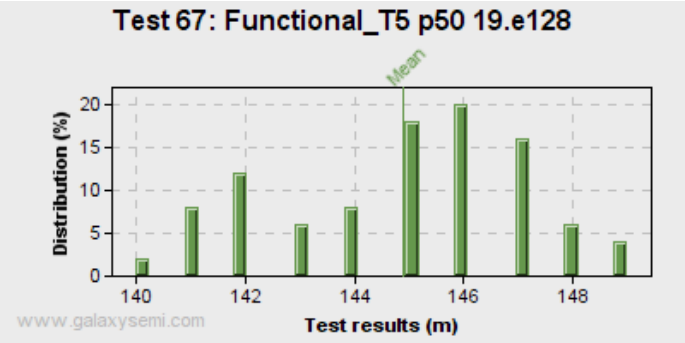
Test	64
Name	icc_static_vbt11 vcc 15.e201 <> Icc_static
Test type	Parametric
Low limit	10 uA
High limit	500 uA
Exec / Fails	50 / 0 (0.00%)
Mean	21.2196 uA
Sigma	0.243143 uA
Range	0.944137 uA
Cp / Cpk	335.9 / 15.38
Samples	50



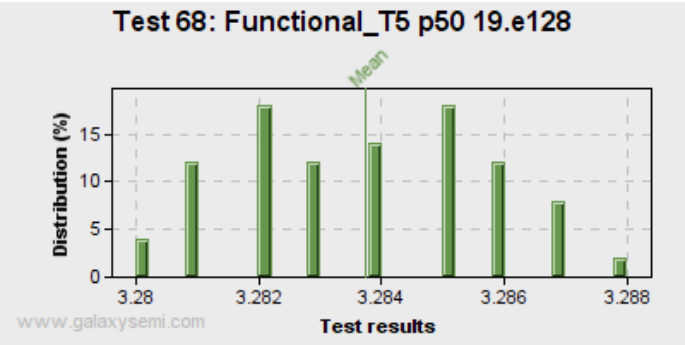
Test	65
Name	Icc_dynamic vcc 15.e201 <> Icc_dynamic
Test type	Parametric
Low limit	10 uA
High limit	500 uA
Exec / Fails	50 / 0 (0.00%)
Mean	20.7699 uA
Sigma	0.320798 uA
Range	2.31743 uA
Cp / Cpk	254.6 / 11.19
Samples	50



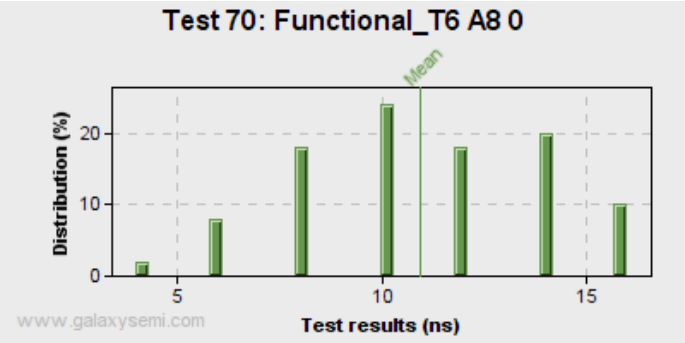
Test	67
Name	Functional_T5 p50 19.e128
Test type	Parametric
Low limit	0 m
High limit	500 m
Exec / Fails	50 / 0 (0.00%)
Mean	144.88 m
Sigma	2.30031 m
Range	9 m
Cp / Cpk	36.23 / 20.99
Samples	50



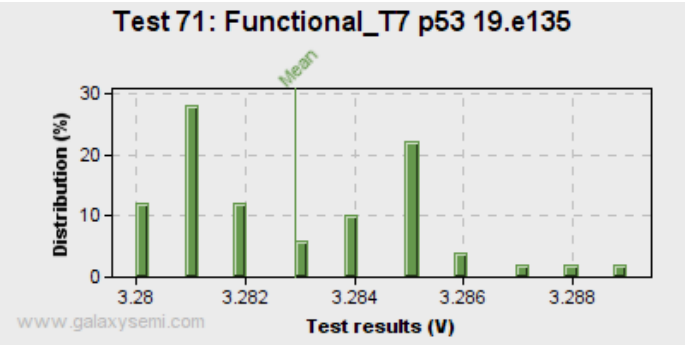
Test	68
Name	Functional_T5 p50 19.e128
Test type	Parametric
Low limit	2.8
High limit	3.4
Exec / Fails	50 / 0 (0.00%)
Mean	3.28374
Sigma	0.00206834
Range	0.00800014
Cp / Cpk	48.35 / 18.74
Samples	50



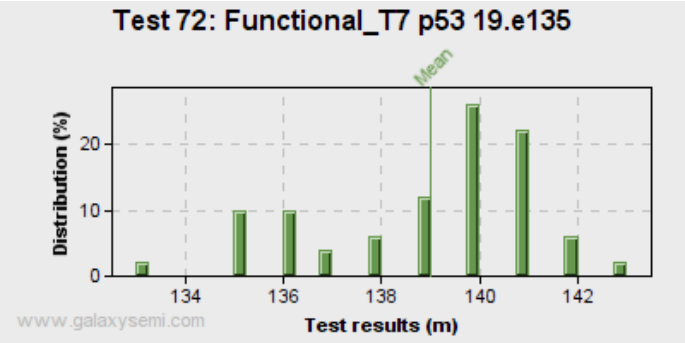
Test	70
Name	Functional_T6 A8 0
Test type	Parametric
Low limit	1 ns
High limit	100 ns
Exec / Fails	50 / 0 (0.00%)
Mean	10.96 ns
Sigma	3.0836 ns
Range	12 ns
Cp / Cpk	5.35 / 1.08
Samples	50



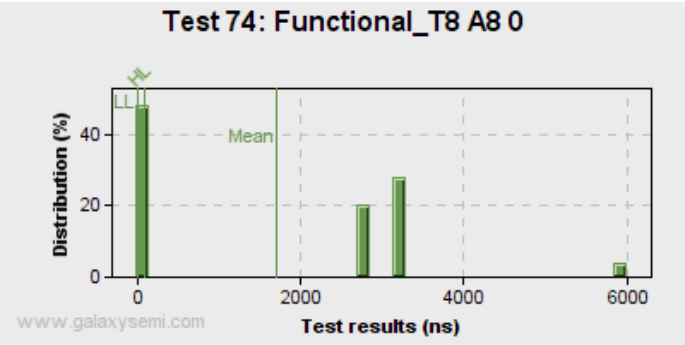
Test	71
Name	Functional_T7 p53 19.e135
Test type	Parametric
Low limit	2.5 V
High limit	3.5 V
Exec / Fails	50 / 0 (0.00%)
Mean	3.28292 V
Sigma	0.00230213 V
Range	0.00900006 V
Cp / Cpk	72.40 / 31.43
Samples	50



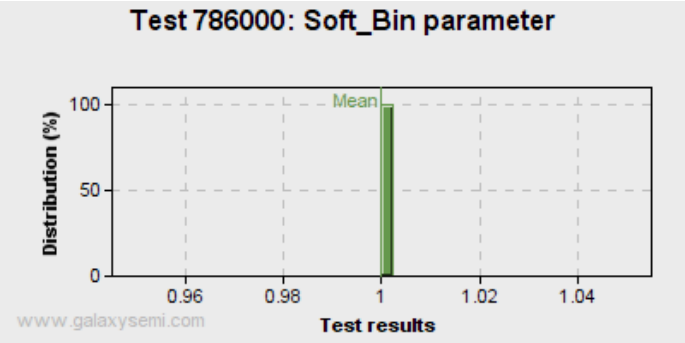
Test	72
Name	Functional_T7 p53 19.e135
Test type	Parametric
Low limit	0 m
High limit	500 m
Exec / Fails	50 / 0 (0.00%)
Mean	139 m
Sigma	2.35606 m
Range	10 m
Cp / Cpk	35.37 / 19.67
Samples	50



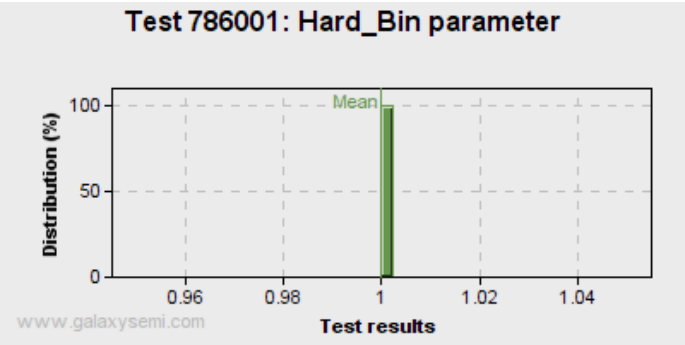
Test	74
Name	Functional_T8 A8 0
Test type	Parametric
Low limit	1 ns
High limit	100 ns
Exec / Fails	50 / 31 (62.00%)
Mean	**1700.48 ns**
Sigma	1752.32 ns
Range	6006 ns
Cp / Cpk	0.0094 / −0.3044 ....=&gt Warning: Process is over the high limit
Samples	50



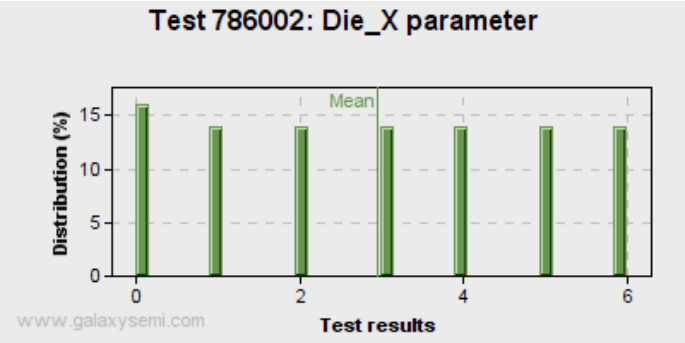
Test	786000
Name	Soft_Bin parameter
Test type	–
Low limit	n/a .
High limit	n/a .
Exec / Fails	50 / 0 (0.00%)
Mean	1
Sigma	0
Range	0
Cp / Cpk	n/a . / n/a .
Samples	50



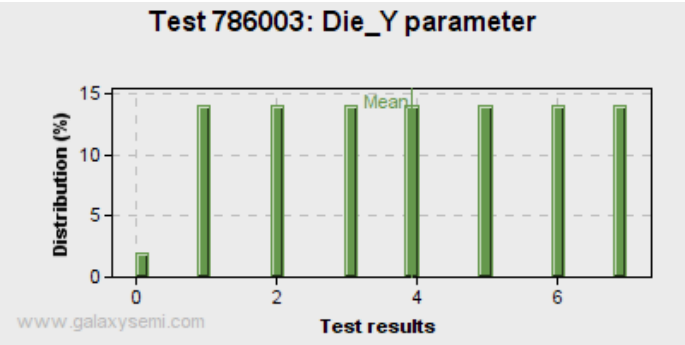
Test	786001
Name	Hard_Bin parameter
Test type	–
Low limit	n/a .
High limit	n/a .
Exec / Fails	50 / 0 (0.00%)
Mean	1
Sigma	0
Range	0
Cp / Cpk	n/a . / n/a .
Samples	50



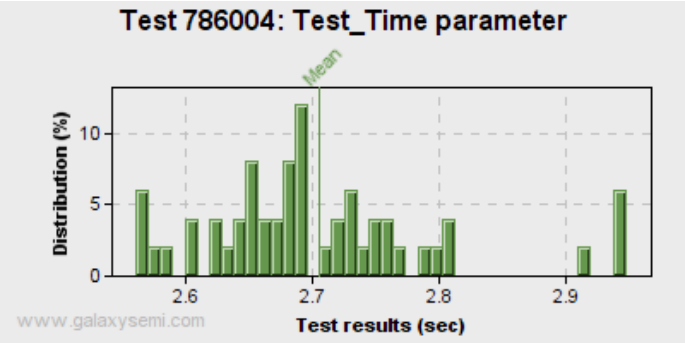
Test	786002
Name	Die_X parameter
Test type	–
Low limit	n/a .
High limit	n/a .
Exec / Fails	50 / 0 (0.00%)
Mean	2.94
Sigma	2.0445
Range	6
Cp / Cpk	n/a . / n/a .
Samples	50



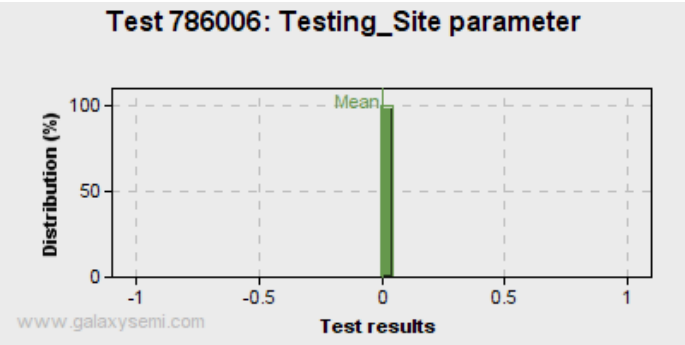
Test	786003
Name	Die_Y parameter
Test type	–
Low limit	n/a .
High limit	n/a .
Exec / Fails	50 / 0 (0.00%)
Mean	3.92
Sigma	2.07846
Range	7
Cp / Cpk	n/a . / n/a .
Samples	50



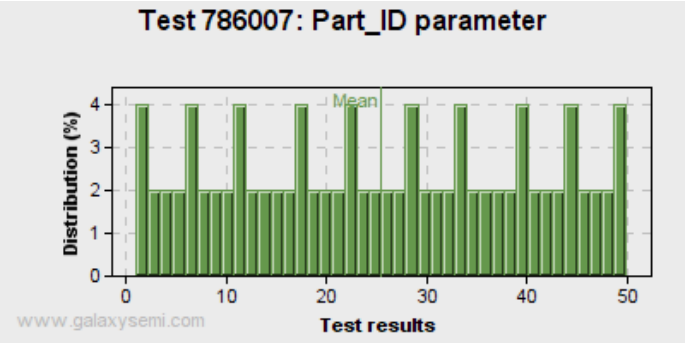
Test	786004
Name	Test_Time parameter
Test type	–
Low limit	0.0 sec
High limit	n/a .
Exec / Fails	50 / 0 (0.00%)
Mean	2.70458 sec
Sigma	0.0934858 sec
Range	0.387 sec
Cp / Cpk	n/a . / 9.64
Samples	50



Test	786006
Name	Testing_Site parameter
Test type	–
Low limit	n/a .
High limit	n/a .
Exec / Fails	50 / 0 (0.00%)
Mean	0
Sigma	0
Range	0
Cp / Cpk	n/a . / n/a .
Samples	50



Test	786007
Name	Part_ID parameter
Test type	–
Low limit	n/a .
High limit	n/a .
Exec / Fails	50 / 0 (0.00%)
Mean	25.5
Sigma	14.5774
Range	49
Cp / Cpk	n/a . / n/a .
Samples	50



Pareto of Tests Cp

Test	Name	Cp	Test Cp Chart
74	Functional_T8 A8 0	0.0094	

Shows all Cp <= 1.7 (Defined in Options , section 'Pareto/Define Cp cut−off limit')

Pareto of Tests Cpk

Test	Name	Cpk	Test Cpk Chart
74	Functional_T8 A8 0	−0.3044	
70	Functional_T6 A8 0	1.08	

Shows all Cpk <= 1.3 (Defined in Options , section 'Pareto/Define Cp cut−off limit')

Pareto of Tests failures

Test	Name	Failing Bin	Failures count	Yield Loss	Fail contribution	Test Fail rate	Failures Chart
74	Functional_T8 A8 0	–	31	62.0 %	n/a	62.0 %	
–	**Cumul. of failures**	–	**31**	**62.0 %**	**0.0 %**	**62.0 %**	

-– Yield loss: number of failed test executions / number of parts
-– Fail contribution: number of failed test executions / number of parts failed
-– Test Fail rate: number of failed test executions / number of test executions

Pareto of Functional Failure Signatures (pins tested in parallel)

Total devices tested: **50**
Total patterns detected: **1**

Fail count	% of failures	% of tested	Functional Failure signatures (tested pins failing together)
31	100.00 %	62.00 %	Functional_T8 A8 0 (Test 74)
31	**100 %**	**–**	**Total failures detected**

Shows first 25 % of the failure signatures (Defined in Options, section 'Pareto/Define Failure Signatures cut−off limit')

Pareto of Parametric Failure Signatures (tests failing concurrently)

No Parametric failure signature detected

Pareto of Software Bins

Software Binning	Bin Name	Count	Percentage	Software Binning Chart
1	–	50	100.0 %	
Cumul.	Cumul.	50	100.0%	

Pareto of Hardware Bins

Hardware Binning	Bin Name	Count	Percentage	Hardware Binning Chart
1	–	50	100.0 %	
Cumul.	Cumul.	50	100.0%	

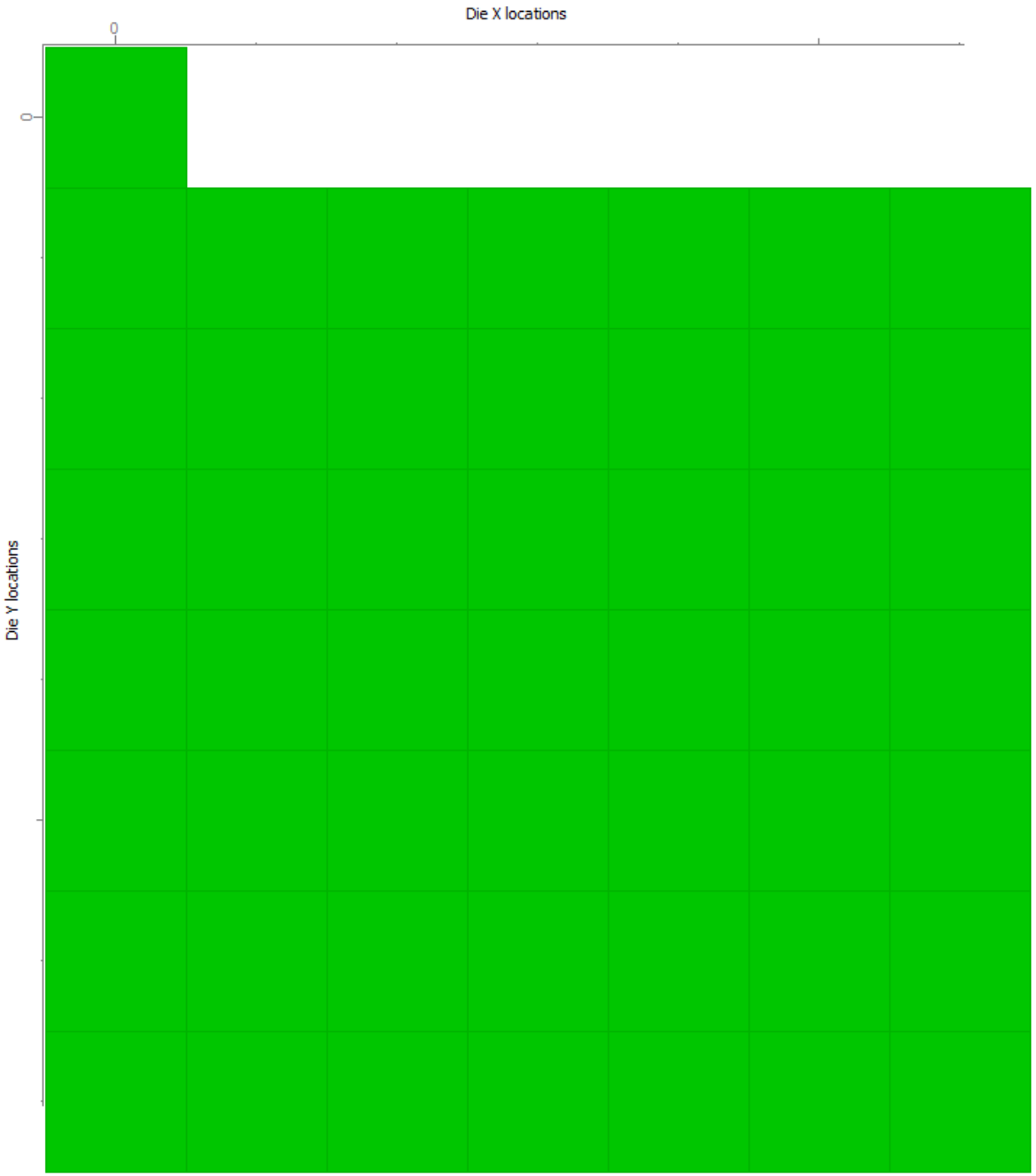
Wafermaps & Strip Maps

Map type	Show Software bins
Devices tested (with retests)	50
Total physical parts tested	50 (only applies to Wafermaps)

List of Individual Maps

Top 10 Software Binning	1
Color	
Pass/Fail	P
Percentage	100.0%
Total count	50

Map style	STRIP map (parts tested are PACKAGED DEVICES!)
Total physical parts tested	50
Parts processed	All Data / parts (any Bin)
Data from Sites	All sites
Strip started	Tue Sep 03 12:30:14 2024
Strip ended	Tue Sep 03 12:33:40 2024
Wafer tested in	3 minutes 26 seconds
Average device test time	4.120 sec.
Map dimensions	LowX=0, LowY=0, HighX=6, HighY=7


Die X locations
0
0
Die Y locations


Run 1, Run 2,...

Software Binning Summary

Software Binning	Bin Name	Pass/ Fail	Total count	Percentage	Software Binning Chart
1	–	P	50	100.0 %	
All PASS Bins	**All PASS Bins**	P	**50**	**100.0 %**	
ALL Bins	**ALL Bins**	–	**50**	**100.0 %**	

Hint: From the 'Options' tab in the 'Binning' section, you can configure how to compute the binning (from summary or samples)

Hardware Binning Summary

Hardware Binning	Bin Name	Pass/ Fail	Total count	Percentage	Hardware Binning Chart
1	–	P	50	100.0 %	
All PASS Bins	All PASS Bins	P	50	100.0 %	
ALL Bins	ALL Bins	–	50	100.0 %	

Hint: From the 'Options' tab in the 'Binning' section, you can configure how to compute the binning (from summary or samples)

Message Log

No log message to report

Global Information

Report from	Teradyne–Examinator–Pro+ – V8.1.5 – www.galaxysemi.com
Report created	Tue Sep 03 00:34:17 2024
Data processed	289.5 KB (296474 bytes)
Processing time	0.79 second
Processing speed	374.8 KB/sec
Examinator expires	Sat Sep 2 2034
(null)	–
File name	C:/Users/rahmana/OneDrive – Teradyne/Desktop/New Hire/New Hire Tech/UFP New Hire Train/Project 1/i8243/results_V2_50loop.std
Tests mapping file	n/a

Setup time	Tue Sep 03 12:30:14 2024
Start time	Tue Sep 03 12:30:14 2024
End time	Tue Sep 03 12:33:40 2024
Test duration	3 minutes 26 seconds
Product	n/a
Program	rahmana_i8243_p1.igxl
Revision	n/a
Lot	n/a
Sub−Lot	n/a
WaferID	n/a
Parts processed	All Data / parts (any Bin)
Data from Sites	All sites
Test time (GOOD parts)	2.705 sec. (excludes tester idle time)
Test time (ALL parts)	2.705 sec. (excludes tester idle time)
Average test time	4.120 sec. / device (includes tester idle time between parts)
Total parts tested	50 − Includes parts retested (if any)
Good parts (Yield)	50 (100.00%) − Includes parts retested (if any)
Bad parts (Yield loss)	0 (0.00%) − Includes parts retested (if any)
Parts retested	n/a .
Parts aborted	0 (0.00%)
(null)	−
STDF Version	4.0
Tester name	SNG−UFP−789
Tester type	UltraFLEXplus
Station	1
Part type	n/a
Operator	rahmana
Exec_type	IG−XL
Exec_version	10.30.10_uflx (P1.11)
TestCode	n/a
Test Temperature	n/a
User Text	n/a
Aux_file	n/a
Package type	n/a
Per_freq	n/a
Spec_name	n/a
Spec_version	n/a
Family ID	n/a

Date code	n/a
Design Rev	n/a
Facility ID	n/a
Floor ID	n/a
Proc ID	n/a
Flow ID	n/a
Setup ID	n/a
Eng ID	n/a
ROM code	n/a
Serial #	n/a
Super user name	n/a
Handler/Prober	n/a
(null)	–
Site details	Site# 0

Global Options

Test# policy	Never merge tests with identical test number if test name not matching
Data Cleaning	None (keep all data)
Statistics computation	From samples data (if any), otherwise from summary
Binning computation	From summary data (if any), otherwise from samples
Cp,Cpk computation	Use standard Sigma formula
Mean drift formula	Percentage of value drift